Application/Control No. Applicant(s)/Patent Under Reexamination 09/873,815 LAVORGNA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Tan Dean D. Nguyen 3629 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,684,369 01-2004 Bernardo et al. 715/513 US-2002/0059264 05-2002 Fleming et al. 707/100 В US-2002/0173997 11-2002 Menard et al. 705/7 Ç US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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